www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
Shen Keng Dist, New Taipei City, Taiwan
TEL: +886-2-26620988
FAX: +886-2-26620488

Product/Process Change Notification

PCN#	Effective Date	Issue Date
2014-08-01C-13	2015/2/1	2014/8/1

PCN Classification	Product Category
Major	SOD-723 Package

Subject

Add a molding vendor

Affected Product(s)

SCS521G. SCS520G. SCS751G. SCS400G. SESD03. SESD05. SESD07.SESD12. BZX784B SERIES.

Description of Change(s)

In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new vendor.

Content of Change(s)

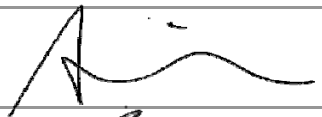
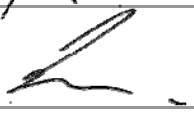
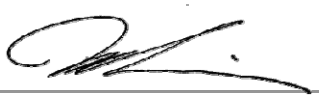
Add Molding vendor--ELER-8-100HFE

Impact(s)

N/A

Attachment(s)

Reliability Teat Report.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

SeCoS Corporation

Reliability Testing Summary Report

Date: 2014/06/30 Document No.: SH14 -06- 34

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SCS520G	100 ± 5℃, 100%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SCS520G	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SCS520G	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SCS520G	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SCS520G	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SCS520G	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	SCS520G	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2014.05.05 Testing End Date: 2014.06.30

Tester: Leo Hsia Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 25℃
Test Date: 2014.05.05 ~ 2014.05.05
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
1	349.4mV	47.74V	0.083uA
2	347.9mV	47.64V	0.081uA
3	346.4mV	46.99V	0.114uA
4	347.2mV	47.33V	0.075uA
5	347.3mV	47.48V	0.079uA
6	345.6mV	47.99V	0.075uA
7	350.3mV	47.19V	0.086uA
8	347.6mV	48.15V	0.076uA
9	348.9mV	47.85V	0.078uA
10	349.3mV	47.15V	0.085uA
11	348.5mV	48.49V	0.099uA
12	346.9mV	47.75V	0.078uA
13	349.8mV	48.09V	0.092uA
14	346.5mV	48.52V	0.092uA
15	349.8mV	47.45V	0.110uA
16	348.0mV	47.31V	0.088uA
17	348.8mV	47.59V	0.080uA
18	346.9mV	47.68V	0.095uA
19	347.9mV	48.21V	0.073uA
20	346.6mV	47.73V	0.093uA
21	349.1mV	47.18V	0.080uA
22	348.3mV	47.31V	0.086uA
23	349.1mV	47.24V	0.098uA
24	347.2mV	47.42V	0.113uA
25	348.1mV	47.18V	0.113uA
26	345.7mV	48.00V	0.091uA
27	347.0mV	47.61V	0.097uA
28	348.5mV	47.75V	0.098uA
29	347.6mV	47.03V	0.096uA
30	346.4mV	47.20V	0.102uA
31	349.0mV	48.45V	0.094uA

SeCoS Corporation

Electrical Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 25℃
Test Date: 2014.05.05 ~ 2014.05.05
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
32	346.4mV	48.42V	0.080uA
33	346.6mV	47.79V	0.113uA
34	346.7mV	47.57V	0.075uA
35	348.3mV	48.16V	0.098uA
36	347.6mV	47.84V	0.111uA
37	348.6mV	47.51V	0.086uA
38	348.9mV	48.25V	0.100uA
39	349.4mV	48.49V	0.078uA
40	347.1mV	47.44V	0.100uA
41	349.6mV	48.34V	0.098uA
42	348.5mV	48.44V	0.111uA
43	349.3mV	47.48V	0.107uA
44	345.3mV	47.56V	0.075uA
45	348.6mV	47.05V	0.077uA
46	348.0mV	47.63V	0.104uA
47	348.0mV	47.39V	0.073uA
48	346.5mV	47.03V	0.088uA
49	347.9mV	46.94V	0.074uA
50	348.3mV	48.52V	0.077uA
51	346.9mV	47.85V	0.088uA
52	350.2mV	48.19V	0.085uA
53	348.9mV	48.03V	0.079uA
54	348.6mV	46.92V	0.085uA
55	346.8mV	47.82V	0.101uA
56	346.9mV	47.53V	0.102uA
57	349.4mV	46.93V	0.113uA
58	345.1mV	47.64V	0.106uA
59	346.1mV	48.24V	0.084uA
60	346.7mV	48.46V	0.080uA
61	347.2mV	47.61V	0.079uA
62	350.0mV	47.14V	0.077uA

SeCoS Corporation

Electrical Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 25℃
Test Date: 2014.05.05 ~ 2014.05.05
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
63	348.3mV	47.62V	0.073uA
64	347.7mV	47.41V	0.106uA
65	345.7mV	47.73V	0.080uA
66	348.2mV	48.07V	0.112uA
67	348.2mV	47.52V	0.084uA
68	347.1mV	47.29V	0.107uA
69	349.1mV	47.77V	0.081uA
70	349.6mV	47.39V	0.078uA
71	347.5mV	47.83V	0.103uA
72	349.5mV	47.83V	0.109uA
73	345.4mV	47.49V	0.098uA
74	348.0mV	48.35V	0.082uA
75	346.4mV	48.46V	0.107uA
76	347.2mV	48.21V	0.075uA
77	349.1mV	47.58V	0.082uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 100 ± 5℃, 100%VR, T = 1000 hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	347.1mV	47.73V	0.073uA	346.9mV	47.43V	0.100uA
2	350.3mV	48.31V	0.104uA	347.8mV	48.41V	0.100uA
3	348.0mV	47.76V	0.108uA	345.1mV	47.25V	0.090uA
4	348.0mV	47.40V	0.115uA	347.9mV	47.25V	0.085uA
5	348.0mV	47.96V	0.095uA	350.2mV	47.53V	0.107uA
6	347.9mV	48.39V	0.104uA	346.2mV	48.08V	0.111uA
7	349.9mV	48.15V	0.085uA	347.5mV	48.37V	0.096uA
8	349.7mV	46.95V	0.073uA	347.7mV	48.15V	0.114uA
9	346.4mV	46.97V	0.073uA	350.3mV	47.32V	0.084uA
10	346.8mV	47.56V	0.074uA	345.4mV	47.19V	0.092uA
11	349.6mV	48.07V	0.081uA	348.6mV	47.37V	0.096uA
12	349.1mV	48.32V	0.073uA	345.8mV	48.41V	0.080uA
13	348.8mV	47.44V	0.105uA	349.7mV	47.64V	0.075uA
14	350.1mV	47.19V	0.086uA	350.3mV	47.73V	0.073uA
15	349.3mV	48.15V	0.096uA	347.0mV	47.95V	0.107uA
16	347.0mV	48.02V	0.094uA	345.9mV	47.29V	0.093uA
17	347.6mV	47.45V	0.075uA	345.5mV	47.65V	0.086uA
18	348.4mV	47.99V	0.084uA	346.3mV	48.16V	0.094uA
19	347.5mV	47.31V	0.109uA	349.9mV	48.51V	0.088uA
20	347.4mV	48.19V	0.091uA	350.2mV	47.56V	0.106uA
21	345.5mV	47.15V	0.081uA	347.5mV	47.88V	0.094uA
22	349.2mV	47.21V	0.104uA	350.1mV	47.91V	0.076uA
23	346.8mV	47.47V	0.106uA	346.0mV	47.62V	0.110uA
24	348.9mV	48.38V	0.075uA	345.5mV	47.26V	0.087uA
25	346.0mV	48.39V	0.082uA	350.2mV	47.53V	0.105uA
26	347.1mV	48.46V	0.076uA	346.9mV	48.22V	0.104uA
27	348.4mV	46.92V	0.083uA	345.6mV	47.20V	0.111uA
28	350.1mV	48.45V	0.113uA	349.2mV	48.18V	0.097uA
29	345.8mV	47.07V	0.084uA	346.3mV	47.32V	0.075uA
30	348.2mV	47.59V	0.077uA	346.7mV	47.41V	0.094uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 100 ± 5℃, 100%VR, T = 1000 hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	349.3mV	47.22V	0.090uA	348.7mV	47.72V	0.079uA
32	346.8mV	46.97V	0.074uA	345.1mV	47.57V	0.103uA
33	347.1mV	47.31V	0.114uA	348.5mV	48.27V	0.115uA
34	346.1mV	47.92V	0.115uA	346.1mV	47.53V	0.100uA
35	349.8mV	47.42V	0.079uA	348.8mV	47.83V	0.113uA
36	350.0mV	47.92V	0.096uA	349.4mV	47.67V	0.088uA
37	349.8mV	47.71V	0.086uA	349.4mV	48.07V	0.108uA
38	347.5mV	47.18V	0.090uA	348.3mV	47.97V	0.110uA
39	345.2mV	47.89V	0.108uA	348.9mV	47.61V	0.096uA
40	345.4mV	47.44V	0.084uA	346.9mV	47.15V	0.099uA
41	348.2mV	47.01V	0.092uA	345.6mV	47.74V	0.110uA
42	346.6mV	47.41V	0.102uA	349.3mV	47.75V	0.080uA
43	345.6mV	46.95V	0.110uA	348.9mV	48.46V	0.074uA
44	348.4mV	47.42V	0.113uA	346.2mV	47.79V	0.076uA
45	345.3mV	47.05V	0.101uA	349.9mV	47.21V	0.101uA
46	345.8mV	48.36V	0.111uA	345.2mV	47.87V	0.087uA
47	348.6mV	48.23V	0.076uA	349.3mV	47.27V	0.088uA
48	345.9mV	48.15V	0.080uA	347.0mV	47.56V	0.084uA
49	347.5mV	47.78V	0.079uA	346.8mV	47.09V	0.072uA
50	347.0mV	48.12V	0.089uA	345.8mV	47.83V	0.086uA
51	345.3mV	48.36V	0.112uA	348.7mV	47.57V	0.081uA
52	345.7mV	47.24V	0.091uA	348.5mV	47.95V	0.083uA
53	348.7mV	47.47V	0.083uA	346.4mV	47.17V	0.094uA
54	347.4mV	47.64V	0.083uA	349.9mV	47.75V	0.085uA
55	348.5mV	46.97V	0.092uA	347.2mV	47.37V	0.097uA
56	349.0mV	48.50V	0.108uA	349.5mV	47.50V	0.085uA
57	346.8mV	47.91V	0.105uA	348.7mV	47.98V	0.088uA
58	345.2mV	48.11V	0.102uA	349.3mV	48.37V	0.106uA
59	346.0mV	48.33V	0.090uA	350.1mV	48.53V	0.081uA
60	350.3mV	47.04V	0.090uA	346.5mV	48.42V	0.086uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 100 ± 5℃, 100%VR, T = 1000 hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	349.0mV	47.66V	0.077uA	347.1mV	47.78V	0.101uA
62	348.8mV	47.14V	0.111uA	349.6mV	47.08V	0.078uA
63	346.0mV	47.77V	0.092uA	347.1mV	48.11V	0.087uA
64	346.5mV	47.31V	0.077uA	345.8mV	47.39V	0.076uA
65	346.9mV	47.35V	0.089uA	345.8mV	47.05V	0.078uA
66	346.8mV	47.37V	0.113uA	349.8mV	47.13V	0.084uA
67	349.2mV	47.58V	0.106uA	348.1mV	48.36V	0.106uA
68	347.2mV	48.33V	0.106uA	345.9mV	48.37V	0.090uA
69	346.0mV	46.92V	0.079uA	348.8mV	47.48V	0.090uA
70	347.6mV	47.78V	0.104uA	348.3mV	47.62V	0.084uA
71	345.6mV	47.08V	0.107uA	345.4mV	47.78V	0.111uA
72	346.7mV	47.42V	0.114uA	349.4mV	47.42V	0.094uA
73	349.0mV	47.13V	0.096uA	347.0mV	47.51V	0.107uA
74	345.4mV	47.54V	0.115uA	348.2mV	46.99V	0.103uA
75	349.8mV	47.78V	0.108uA	346.9mV	47.27V	0.082uA
76	350.2mV	47.99V	0.088uA	345.7mV	46.94V	0.079uA
77	349.2mV	47.00V	0.093uA	347.3mV	47.07V	0.102uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	350.2mV	47.52V	0.084uA	349.8mV	48.30V	0.094uA
2	348.5mV	47.43V	0.093uA	349.8mV	46.99V	0.084uA
3	346.2mV	48.38V	0.097uA	348.6mV	47.28V	0.112uA
4	348.0mV	46.91V	0.092uA	346.4mV	48.24V	0.109uA
5	349.4mV	47.51V	0.091uA	349.9mV	48.23V	0.080uA
6	350.2mV	47.62V	0.089uA	347.4mV	48.11V	0.108uA
7	345.5mV	48.31V	0.088uA	348.4mV	47.23V	0.100uA
8	348.8mV	47.98V	0.110uA	349.3mV	46.97V	0.094uA
9	346.8mV	47.69V	0.105uA	347.5mV	47.31V	0.084uA
10	347.4mV	47.75V	0.079uA	348.9mV	47.17V	0.082uA
11	348.5mV	48.21V	0.075uA	348.7mV	47.22V	0.115uA
12	348.4mV	46.95V	0.109uA	350.0mV	48.39V	0.097uA
13	346.1mV	47.12V	0.073uA	346.2mV	47.77V	0.092uA
14	349.5mV	47.95V	0.088uA	346.3mV	47.30V	0.109uA
15	349.5mV	47.79V	0.096uA	348.2mV	47.16V	0.088uA
16	348.5mV	47.21V	0.114uA	346.6mV	47.68V	0.090uA
17	346.3mV	47.69V	0.114uA	346.8mV	48.03V	0.106uA
18	345.8mV	48.35V	0.099uA	345.4mV	47.11V	0.086uA
19	348.3mV	48.08V	0.086uA	345.8mV	48.29V	0.079uA
20	349.1mV	47.35V	0.093uA	345.8mV	47.56V	0.080uA
21	346.5mV	47.80V	0.079uA	349.9mV	47.10V	0.081uA
22	349.5mV	47.70V	0.078uA	349.4mV	47.82V	0.102uA
23	345.2mV	48.14V	0.073uA	347.1mV	47.54V	0.097uA
24	345.8mV	47.77V	0.089uA	345.3mV	47.46V	0.105uA
25	349.3mV	48.23V	0.075uA	349.3mV	47.13V	0.079uA
26	346.9mV	47.71V	0.087uA	345.7mV	48.28V	0.084uA
27	349.1mV	48.31V	0.083uA	346.9mV	47.43V	0.089uA
28	348.5mV	48.16V	0.074uA	345.6mV	48.37V	0.079uA
29	349.9mV	48.52V	0.080uA	348.6mV	47.33V	0.075uA
30	348.3mV	48.06V	0.099uA	349.7mV	48.38V	0.115uA

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	348.6mV	46.97V	0.112uA	348.5mV	47.21V	0.082uA
32	350.2mV	47.73V	0.104uA	345.4mV	47.57V	0.103uA
33	346.7mV	48.33V	0.106uA	347.2mV	47.82V	0.082uA
34	346.7mV	48.34V	0.115uA	347.6mV	47.36V	0.113uA
35	348.9mV	47.88V	0.089uA	345.6mV	48.14V	0.075uA
36	348.8mV	47.10V	0.091uA	345.8mV	47.67V	0.113uA
37	347.2mV	47.78V	0.103uA	349.5mV	46.92V	0.093uA
38	349.2mV	47.31V	0.090uA	350.3mV	48.19V	0.080uA
39	345.7mV	47.22V	0.108uA	346.9mV	47.03V	0.095uA
40	349.6mV	48.31V	0.101uA	345.4mV	48.40V	0.102uA
41	345.9mV	47.35V	0.106uA	347.2mV	47.82V	0.076uA
42	349.4mV	47.36V	0.094uA	348.6mV	47.58V	0.083uA
43	348.5mV	46.90V	0.087uA	345.2mV	47.62V	0.079uA
44	345.4mV	47.14V	0.113uA	349.1mV	47.75V	0.102uA
45	345.5mV	46.92V	0.090uA	345.3mV	48.21V	0.100uA
46	349.8mV	47.35V	0.096uA	350.1mV	47.81V	0.087uA
47	347.9mV	47.45V	0.106uA	349.9mV	48.02V	0.097uA
48	345.1mV	47.98V	0.090uA	345.4mV	47.72V	0.081uA
49	350.3mV	47.16V	0.096uA	346.7mV	46.96V	0.114uA
50	345.6mV	48.26V	0.110uA	350.2mV	48.43V	0.100uA
51	347.3mV	48.09V	0.109uA	347.0mV	48.52V	0.099uA
52	349.6mV	47.24V	0.102uA	348.0mV	47.95V	0.106uA
53	346.9mV	47.59V	0.112uA	350.4mV	47.27V	0.075uA
54	346.8mV	47.81V	0.109uA	349.3mV	46.92V	0.094uA
55	345.3mV	47.17V	0.074uA	347.9mV	48.28V	0.086uA
56	346.0mV	47.73V	0.078uA	347.1mV	48.27V	0.073uA
57	346.9mV	48.22V	0.076uA	345.5mV	48.14V	0.111uA
58	349.1mV	48.17V	0.109uA	345.4mV	46.98V	0.098uA
59	348.0mV	47.29V	0.111uA	347.9mV	48.26V	0.104uA
60	349.7mV	47.24V	0.086uA	345.9mV	48.00V	0.080uA

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.05.05 ~ 2014.06.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	345.4mV	48.30V	0.072uA	346.3mV	47.07V	0.105uA
62	345.9mV	48.18V	0.113uA	346.6mV	48.39V	0.080uA
63	348.4mV	47.40V	0.110uA	345.9mV	48.00V	0.072uA
64	348.8mV	47.38V	0.115uA	349.4mV	48.27V	0.072uA
65	348.9mV	48.40V	0.109uA	347.9mV	47.20V	0.105uA
66	345.5mV	47.88V	0.093uA	348.8mV	46.98V	0.075uA
67	345.5mV	47.09V	0.100uA	345.2mV	48.10V	0.082uA
68	345.9mV	48.21V	0.078uA	348.5mV	47.62V	0.109uA
69	349.4mV	46.93V	0.102uA	348.3mV	48.20V	0.101uA
70	345.4mV	47.79V	0.087uA	347.0mV	48.15V	0.110uA
71	348.4mV	47.59V	0.079uA	345.5mV	47.87V	0.096uA
72	345.7mV	47.41V	0.072uA	350.3mV	47.22V	0.106uA
73	345.9mV	48.46V	0.085uA	349.6mV	47.40V	0.097uA
74	346.1mV	47.03V	0.087uA	347.7mV	47.95V	0.087uA
75	348.6mV	48.06V	0.103uA	349.3mV	48.51V	0.104uA
76	347.0mV	48.47V	0.108uA	348.6mV	47.94V	0.096uA
77	349.5mV	47.20V	0.100uA	348.4mV	48.35V	0.093uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.05.05 ~ 2014.05.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	345.1mV	48.22V	0.083uA	347.0mV	47.30V	0.094uA
2	348.4mV	48.20V	0.081uA	345.5mV	47.93V	0.108uA
3	349.3mV	48.04V	0.105uA	349.2mV	47.21V	0.090uA
4	347.5mV	46.98V	0.095uA	348.8mV	47.39V	0.099uA
5	347.5mV	48.34V	0.073uA	347.6mV	48.12V	0.092uA
6	350.3mV	47.49V	0.103uA	350.2mV	47.80V	0.079uA
7	345.6mV	47.17V	0.100uA	349.3mV	48.17V	0.087uA
8	346.4mV	47.48V	0.096uA	350.3mV	48.45V	0.086uA
9	345.8mV	48.14V	0.095uA	348.4mV	47.81V	0.102uA
10	350.2mV	47.79V	0.075uA	350.3mV	47.91V	0.106uA
11	349.5mV	47.26V	0.104uA	346.0mV	47.50V	0.104uA
12	345.8mV	48.33V	0.088uA	346.8mV	47.43V	0.098uA
13	346.7mV	48.21V	0.078uA	350.2mV	48.28V	0.114uA
14	345.5mV	47.44V	0.087uA	349.6mV	47.17V	0.111uA
15	349.4mV	48.15V	0.081uA	347.8mV	48.25V	0.100uA
16	346.0mV	47.54V	0.101uA	349.3mV	47.76V	0.092uA
17	347.2mV	47.74V	0.077uA	347.4mV	47.41V	0.106uA
18	345.9mV	48.41V	0.115uA	346.1mV	47.83V	0.083uA
19	345.3mV	47.99V	0.108uA	348.8mV	47.86V	0.076uA
20	346.5mV	47.30V	0.081uA	349.1mV	48.11V	0.101uA
21	348.9mV	48.18V	0.112uA	345.5mV	46.92V	0.113uA
22	347.8mV	47.72V	0.113uA	346.6mV	48.19V	0.110uA
23	348.3mV	48.03V	0.103uA	348.8mV	47.41V	0.082uA
24	345.2mV	47.87V	0.111uA	347.5mV	47.19V	0.107uA
25	345.9mV	47.32V	0.076uA	348.7mV	47.38V	0.083uA
26	349.2mV	47.06V	0.107uA	347.6mV	47.25V	0.101uA
27	345.1mV	48.49V	0.107uA	345.2mV	48.14V	0.086uA
28	348.9mV	48.29V	0.113uA	347.2mV	47.71V	0.103uA
29	347.4mV	47.87V	0.112uA	347.8mV	47.97V	0.098uA
30	349.7mV	47.62V	0.093uA	346.7mV	47.17V	0.101uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.05.05 ~ 2014.05.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	347.3mV	47.50V	0.098uA	348.6mV	47.97V	0.085uA
32	349.0mV	48.05V	0.078uA	348.6mV	47.46V	0.084uA
33	346.1mV	47.40V	0.092uA	346.4mV	47.61V	0.093uA
34	349.8mV	47.84V	0.094uA	346.1mV	48.52V	0.074uA
35	348.8mV	47.17V	0.080uA	347.7mV	47.59V	0.094uA
36	345.6mV	47.84V	0.103uA	346.2mV	47.88V	0.087uA
37	350.3mV	48.20V	0.101uA	350.2mV	47.34V	0.074uA
38	346.3mV	48.40V	0.112uA	348.5mV	47.08V	0.087uA
39	348.3mV	47.21V	0.093uA	346.8mV	47.08V	0.089uA
40	348.6mV	47.30V	0.110uA	347.8mV	47.79V	0.096uA
41	349.9mV	47.66V	0.089uA	345.1mV	48.53V	0.111uA
42	347.9mV	48.44V	0.077uA	347.3mV	47.46V	0.093uA
43	345.1mV	47.26V	0.079uA	345.5mV	48.28V	0.088uA
44	350.4mV	48.31V	0.078uA	346.4mV	48.10V	0.085uA
45	345.2mV	47.20V	0.098uA	346.4mV	47.25V	0.083uA
46	345.6mV	47.84V	0.084uA	346.1mV	46.92V	0.099uA
47	349.6mV	47.50V	0.086uA	346.9mV	47.55V	0.085uA
48	346.8mV	48.23V	0.074uA	346.6mV	48.00V	0.085uA
49	348.7mV	46.91V	0.088uA	346.1mV	47.06V	0.102uA
50	349.0mV	48.02V	0.094uA	347.6mV	46.97V	0.082uA
51	347.4mV	47.08V	0.114uA	349.4mV	47.48V	0.106uA
52	348.3mV	47.07V	0.093uA	348.1mV	47.73V	0.077uA
53	345.5mV	47.83V	0.112uA	349.0mV	47.01V	0.084uA
54	349.6mV	47.04V	0.106uA	345.1mV	47.07V	0.077uA
55	347.1mV	48.22V	0.103uA	350.3mV	47.34V	0.112uA
56	349.0mV	47.21V	0.108uA	348.8mV	47.44V	0.098uA
57	346.9mV	48.51V	0.100uA	346.7mV	47.70V	0.087uA
58	346.4mV	47.51V	0.107uA	349.0mV	48.14V	0.106uA
59	348.1mV	47.57V	0.104uA	348.0mV	48.02V	0.086uA
60	345.5mV	47.21V	0.101uA	349.1mV	48.18V	0.104uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.05.05 ~ 2014.05.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	349.5mV	47.32V	0.098uA	348.9mV	48.21V	0.097uA
62	345.2mV	48.19V	0.088uA	347.6mV	47.82V	0.093uA
63	350.1mV	47.51V	0.082uA	349.9mV	48.46V	0.102uA
64	347.3mV	48.42V	0.085uA	348.2mV	47.68V	0.107uA
65	348.5mV	48.50V	0.074uA	345.7mV	47.35V	0.078uA
66	350.2mV	48.38V	0.100uA	346.9mV	48.04V	0.084uA
67	349.4mV	47.30V	0.100uA	347.2mV	47.95V	0.113uA
68	348.9mV	47.94V	0.099uA	349.9mV	48.41V	0.092uA
69	347.2mV	47.99V	0.089uA	349.3mV	47.71V	0.107uA
70	348.6mV	47.98V	0.073uA	346.6mV	47.60V	0.086uA
71	346.3mV	47.51V	0.085uA	349.1mV	48.17V	0.081uA
72	346.0mV	47.64V	0.073uA	349.4mV	47.31V	0.073uA
73	345.4mV	46.92V	0.101uA	347.2mV	47.31V	0.084uA
74	345.2mV	47.09V	0.114uA	345.8mV	47.69V	0.075uA
75	347.2mV	47.20V	0.079uA	348.5mV	47.18V	0.111uA
76	347.9mV	47.46V	0.112uA	349.1mV	48.09V	0.110uA
77	346.8mV	47.19V	0.113uA	348.5mV	48.31V	0.105uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.05.05 ~ 2014.06.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	349.1mV	47.85V	0.083uA	350.1mV	47.90V	0.082uA
2	349.1mV	48.48V	0.110uA	348.9mV	48.03V	0.103uA
3	347.9mV	47.88V	0.084uA	347.7mV	47.57V	0.109uA
4	347.1mV	47.90V	0.097uA	347.6mV	47.69V	0.077uA
5	345.5mV	48.46V	0.102uA	348.5mV	48.39V	0.106uA
6	346.4mV	47.32V	0.086uA	349.1mV	47.41V	0.079uA
7	346.6mV	47.27V	0.095uA	349.1mV	48.44V	0.097uA
8	346.8mV	47.55V	0.099uA	349.8mV	47.50V	0.103uA
9	348.5mV	47.35V	0.105uA	349.7mV	48.21V	0.110uA
10	348.9mV	48.50V	0.097uA	349.7mV	47.21V	0.085uA
11	348.4mV	48.52V	0.073uA	350.3mV	48.23V	0.111uA
12	347.9mV	48.28V	0.081uA	347.7mV	47.00V	0.075uA
13	346.3mV	47.83V	0.102uA	348.1mV	47.90V	0.114uA
14	345.9mV	47.35V	0.106uA	346.3mV	47.24V	0.090uA
15	349.4mV	47.54V	0.085uA	348.8mV	48.44V	0.097uA
16	349.4mV	47.50V	0.111uA	349.3mV	48.46V	0.105uA
17	348.5mV	47.97V	0.074uA	349.7mV	47.25V	0.098uA
18	348.3mV	47.89V	0.082uA	350.3mV	48.48V	0.105uA
19	346.6mV	47.76V	0.075uA	349.8mV	47.55V	0.084uA
20	346.9mV	47.26V	0.086uA	349.4mV	47.42V	0.115uA
21	349.2mV	48.12V	0.079uA	346.4mV	47.54V	0.105uA
22	347.8mV	48.22V	0.108uA	349.5mV	48.41V	0.083uA
23	345.7mV	48.33V	0.114uA	345.6mV	48.49V	0.098uA
24	347.5mV	48.02V	0.094uA	345.5mV	48.24V	0.081uA
25	350.0mV	47.10V	0.109uA	347.2mV	47.72V	0.105uA
26	347.4mV	48.16V	0.098uA	347.4mV	48.11V	0.095uA
27	349.0mV	48.08V	0.075uA	348.1mV	48.09V	0.085uA
28	350.3mV	47.90V	0.115uA	348.7mV	46.99V	0.096uA
29	350.0mV	47.79V	0.088uA	345.6mV	47.18V	0.084uA
30	348.4mV	48.03V	0.087uA	346.5mV	47.70V	0.094uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.05.05 ~ 2014.06.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	345.9mV	48.41V	0.095uA	347.7mV	47.31V	0.084uA
32	345.4mV	47.08V	0.112uA	347.8mV	47.54V	0.086uA
33	347.2mV	47.80V	0.098uA	347.4mV	47.17V	0.090uA
34	349.2mV	48.33V	0.074uA	348.8mV	47.35V	0.076uA
35	350.0mV	47.17V	0.089uA	345.4mV	48.27V	0.073uA
36	346.1mV	46.96V	0.103uA	346.3mV	47.69V	0.088uA
37	350.0mV	48.28V	0.082uA	350.3mV	47.06V	0.085uA
38	348.8mV	47.29V	0.080uA	349.4mV	48.23V	0.102uA
39	346.2mV	47.69V	0.100uA	347.3mV	47.89V	0.087uA
40	348.7mV	47.61V	0.081uA	347.4mV	47.34V	0.111uA
41	349.0mV	47.18V	0.076uA	345.3mV	47.69V	0.092uA
42	346.5mV	47.42V	0.085uA	346.5mV	48.07V	0.087uA
43	345.3mV	48.52V	0.082uA	349.4mV	47.08V	0.110uA
44	350.1mV	47.37V	0.080uA	347.6mV	47.41V	0.104uA
45	345.8mV	47.40V	0.102uA	346.1mV	47.97V	0.083uA
46	346.4mV	47.60V	0.111uA	346.7mV	48.35V	0.081uA
47	348.1mV	48.48V	0.103uA	349.1mV	48.45V	0.096uA
48	347.9mV	47.70V	0.089uA	347.3mV	47.46V	0.080uA
49	348.3mV	47.95V	0.101uA	350.1mV	48.04V	0.077uA
50	347.5mV	47.42V	0.086uA	346.3mV	47.06V	0.073uA
51	348.2mV	47.50V	0.105uA	349.2mV	47.19V	0.093uA
52	349.3mV	47.18V	0.076uA	349.3mV	48.05V	0.088uA
53	349.4mV	47.33V	0.105uA	346.4mV	47.92V	0.094uA
54	348.9mV	48.53V	0.095uA	346.0mV	47.43V	0.097uA
55	346.3mV	47.61V	0.103uA	347.7mV	47.24V	0.086uA
56	346.1mV	48.46V	0.093uA	347.3mV	48.27V	0.106uA
57	347.1mV	47.60V	0.080uA	346.3mV	48.02V	0.098uA
58	349.4mV	48.37V	0.100uA	348.2mV	47.57V	0.095uA
59	345.5mV	47.20V	0.095uA	349.5mV	47.45V	0.077uA
60	350.2mV	47.73V	0.084uA	346.4mV	47.35V	0.108uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.05.05 ~ 2014.06.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	350.4mV	47.32V	0.082uA	345.6mV	48.45V	0.100uA
62	349.6mV	47.45V	0.097uA	346.0mV	47.26V	0.095uA
63	348.7mV	47.08V	0.112uA	349.7mV	47.82V	0.108uA
64	346.1mV	47.90V	0.076uA	345.4mV	47.49V	0.107uA
65	346.8mV	47.29V	0.079uA	347.1mV	47.95V	0.080uA
66	346.4mV	47.68V	0.099uA	349.6mV	47.31V	0.105uA
67	346.2mV	48.44V	0.087uA	345.2mV	47.00V	0.102uA
68	348.6mV	47.42V	0.082uA	348.2mV	47.37V	0.092uA
69	349.1mV	47.36V	0.106uA	350.3mV	47.86V	0.088uA
70	347.9mV	47.30V	0.088uA	345.2mV	48.43V	0.114uA
71	349.5mV	48.12V	0.094uA	345.1mV	46.96V	0.086uA
72	347.6mV	47.59V	0.095uA	345.5mV	48.25V	0.087uA
73	348.5mV	48.25V	0.112uA	348.1mV	47.85V	0.080uA
74	348.2mV	47.60V	0.111uA	347.1mV	47.08V	0.103uA
75	350.4mV	48.17V	0.108uA	348.4mV	47.74V	0.077uA
76	347.0mV	47.27V	0.114uA	346.4mV	48.33V	0.100uA
77	349.8mV	47.77V	0.077uA	346.7mV	48.14V	0.092uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	346.3mV	48.04V	0.110uA	348.5mV	47.82V	0.088uA
2	348.1mV	47.69V	0.114uA	349.3mV	46.95V	0.086uA
3	348.2mV	48.15V	0.103uA	347.9mV	48.04V	0.086uA
4	345.7mV	47.88V	0.099uA	346.5mV	47.94V	0.107uA
5	345.2mV	47.95V	0.077uA	348.4mV	47.56V	0.091uA
6	345.5mV	48.15V	0.108uA	348.5mV	48.48V	0.114uA
7	348.7mV	47.51V	0.096uA	348.2mV	47.61V	0.078uA
8	349.1mV	47.76V	0.095uA	347.7mV	47.40V	0.085uA
9	345.3mV	47.38V	0.110uA	347.1mV	47.77V	0.107uA
10	348.6mV	47.50V	0.107uA	349.4mV	47.98V	0.114uA
11	350.0mV	47.00V	0.077uA	348.2mV	48.34V	0.086uA
12	347.5mV	47.84V	0.103uA	349.5mV	47.39V	0.076uA
13	346.1mV	47.01V	0.080uA	350.3mV	47.18V	0.077uA
14	347.7mV	47.62V	0.107uA	348.9mV	46.99V	0.101uA
15	348.4mV	47.70V	0.089uA	348.8mV	47.46V	0.080uA
16	347.3mV	47.20V	0.083uA	345.9mV	47.29V	0.087uA
17	349.6mV	48.44V	0.085uA	345.8mV	47.19V	0.083uA
18	347.5mV	48.26V	0.105uA	346.8mV	48.38V	0.110uA
19	347.6mV	47.66V	0.096uA	349.2mV	47.09V	0.103uA
20	347.6mV	47.20V	0.084uA	348.6mV	48.28V	0.090uA
21	345.7mV	47.93V	0.083uA	348.8mV	48.38V	0.093uA
22	347.1mV	47.11V	0.114uA	348.4mV	47.03V	0.099uA
23	346.2mV	47.53V	0.110uA	348.9mV	47.40V	0.104uA
24	350.4mV	47.52V	0.086uA	347.6mV	47.57V	0.103uA
25	345.8mV	48.50V	0.094uA	348.2mV	48.12V	0.104uA
26	347.0mV	47.53V	0.111uA	348.8mV	47.96V	0.104uA
27	348.6mV	47.66V	0.076uA	350.4mV	48.32V	0.106uA
28	349.6mV	48.31V	0.075uA	349.1mV	47.46V	0.079uA
29	346.4mV	47.31V	0.081uA	348.5mV	48.15V	0.074uA
30	345.6mV	46.95V	0.073uA	345.7mV	48.31V	0.083uA

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	347.5mV	47.84V	0.096uA	346.1mV	48.48V	0.092uA
32	349.8mV	48.21V	0.075uA	345.9mV	47.93V	0.098uA
33	346.2mV	48.01V	0.086uA	345.5mV	47.40V	0.108uA
34	348.4mV	48.23V	0.080uA	347.3mV	47.06V	0.090uA
35	348.2mV	47.93V	0.113uA	349.5mV	47.97V	0.088uA
36	348.0mV	47.32V	0.079uA	349.3mV	47.25V	0.074uA
37	349.1mV	47.10V	0.098uA	345.4mV	47.69V	0.086uA
38	347.2mV	48.36V	0.087uA	350.0mV	47.16V	0.112uA
39	349.7mV	48.28V	0.099uA	345.7mV	48.24V	0.074uA
40	348.5mV	47.06V	0.080uA	350.0mV	47.46V	0.082uA
41	347.9mV	47.62V	0.108uA	349.4mV	47.13V	0.077uA
42	348.3mV	47.95V	0.088uA	347.8mV	47.23V	0.090uA
43	346.8mV	47.82V	0.094uA	347.9mV	47.98V	0.107uA
44	346.5mV	48.44V	0.080uA	346.7mV	47.77V	0.089uA
45	349.4mV	48.21V	0.075uA	349.2mV	47.74V	0.085uA
46	348.3mV	47.85V	0.076uA	349.7mV	47.12V	0.090uA
47	346.7mV	48.28V	0.106uA	345.1mV	47.47V	0.075uA
48	348.9mV	47.77V	0.107uA	347.5mV	47.75V	0.083uA
49	345.6mV	48.43V	0.098uA	349.6mV	47.03V	0.072uA
50	350.0mV	48.25V	0.099uA	347.6mV	48.11V	0.088uA
51	349.8mV	48.25V	0.073uA	346.2mV	47.73V	0.092uA
52	348.9mV	47.94V	0.099uA	348.0mV	48.47V	0.087uA
53	348.7mV	47.10V	0.093uA	346.5mV	47.19V	0.086uA
54	345.5mV	47.07V	0.100uA	349.6mV	48.45V	0.085uA
55	348.3mV	48.51V	0.115uA	346.2mV	47.33V	0.072uA
56	345.6mV	47.78V	0.096uA	347.4mV	47.03V	0.088uA
57	347.1mV	47.72V	0.105uA	345.9mV	47.85V	0.113uA
58	347.3mV	48.14V	0.105uA	348.0mV	47.78V	0.107uA
59	347.6mV	47.20V	0.084uA	345.3mV	48.32V	0.100uA
60	347.3mV	48.25V	0.089uA	347.5mV	48.12V	0.089uA

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	347.9mV	47.46V	0.078uA	346.7mV	47.81V	0.113uA
62	347.0mV	47.87V	0.093uA	346.6mV	47.88V	0.093uA
63	345.8mV	47.98V	0.107uA	346.6mV	47.25V	0.087uA
64	347.1mV	47.25V	0.098uA	347.7mV	47.94V	0.094uA
65	348.8mV	47.43V	0.075uA	348.5mV	47.39V	0.083uA
66	346.1mV	47.38V	0.078uA	346.1mV	48.35V	0.114uA
67	346.4mV	48.08V	0.073uA	349.3mV	48.17V	0.081uA
68	350.2mV	47.78V	0.101uA	347.6mV	47.42V	0.096uA
69	349.6mV	47.60V	0.077uA	349.0mV	48.12V	0.109uA
70	348.1mV	47.48V	0.073uA	348.6mV	47.94V	0.104uA
71	349.6mV	47.08V	0.095uA	346.8mV	47.31V	0.108uA
72	348.4mV	47.03V	0.109uA	345.3mV	48.09V	0.095uA
73	349.7mV	48.45V	0.105uA	347.2mV	47.21V	0.090uA
74	345.3mV	47.62V	0.084uA	348.7mV	47.41V	0.114uA
75	347.2mV	47.03V	0.108uA	349.0mV	47.35V	0.108uA
76	348.4mV	48.23V	0.105uA	346.8mV	47.23V	0.115uA
77	345.5mV	48.34V	0.078uA	345.1mV	46.91V	0.079uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	345.2mV	47.11V	0.076uA	350.3mV	46.99V	0.113uA
2	350.2mV	47.74V	0.106uA	348.0mV	47.23V	0.102uA
3	348.0mV	47.49V	0.111uA	348.8mV	48.37V	0.109uA
4	345.9mV	48.33V	0.105uA	348.0mV	47.01V	0.096uA
5	350.1mV	47.58V	0.079uA	349.7mV	48.38V	0.080uA
6	346.9mV	46.98V	0.094uA	349.6mV	47.47V	0.081uA
7	348.1mV	47.09V	0.088uA	347.4mV	47.52V	0.090uA
8	348.9mV	48.03V	0.096uA	350.0mV	47.77V	0.082uA
9	349.5mV	47.93V	0.102uA	345.3mV	47.06V	0.091uA
10	349.6mV	47.18V	0.081uA	348.1mV	48.29V	0.081uA
11	349.1mV	47.51V	0.093uA	345.4mV	48.08V	0.091uA
12	347.5mV	47.90V	0.094uA	346.9mV	48.48V	0.085uA
13	347.4mV	48.36V	0.081uA	350.2mV	48.24V	0.112uA
14	346.2mV	47.48V	0.091uA	348.8mV	47.32V	0.090uA
15	348.2mV	46.98V	0.112uA	345.1mV	47.45V	0.088uA
16	345.6mV	47.76V	0.090uA	347.6mV	47.42V	0.083uA
17	350.1mV	47.92V	0.081uA	345.9mV	48.49V	0.109uA
18	347.8mV	48.35V	0.096uA	346.9mV	48.26V	0.115uA
19	350.2mV	46.96V	0.103uA	346.7mV	48.37V	0.113uA
20	347.3mV	47.75V	0.088uA	347.4mV	47.71V	0.106uA
21	348.3mV	47.55V	0.101uA	346.1mV	48.29V	0.110uA
22	347.8mV	48.06V	0.095uA	348.4mV	48.04V	0.105uA
23	346.1mV	47.11V	0.107uA	348.5mV	47.67V	0.094uA
24	349.2mV	47.92V	0.077uA	345.6mV	47.12V	0.107uA
25	349.1mV	48.28V	0.108uA	349.9mV	47.16V	0.105uA
26	348.1mV	47.17V	0.103uA	348.4mV	47.03V	0.075uA
27	347.7mV	48.42V	0.100uA	347.4mV	47.86V	0.073uA
28	347.1mV	47.35V	0.112uA	348.9mV	47.58V	0.089uA
29	346.9mV	47.51V	0.107uA	348.7mV	48.00V	0.089uA
30	346.9mV	48.13V	0.076uA	347.5mV	48.42V	0.076uA

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	349.2mV	47.66V	0.112uA	349.9mV	47.72V	0.111uA
32	349.8mV	47.18V	0.074uA	350.4mV	47.56V	0.084uA
33	348.3mV	47.43V	0.077uA	350.2mV	47.12V	0.103uA
34	346.3mV	47.20V	0.106uA	345.6mV	47.93V	0.077uA
35	350.3mV	47.61V	0.079uA	348.3mV	47.77V	0.091uA
36	347.7mV	48.39V	0.094uA	348.0mV	48.10V	0.083uA
37	348.1mV	46.97V	0.084uA	349.7mV	48.19V	0.102uA
38	345.9mV	48.18V	0.082uA	346.8mV	47.34V	0.114uA
39	348.2mV	47.82V	0.102uA	347.1mV	47.77V	0.102uA
40	346.8mV	48.25V	0.094uA	349.0mV	48.24V	0.084uA
41	347.8mV	47.97V	0.114uA	346.5mV	47.79V	0.107uA
42	345.6mV	48.32V	0.087uA	346.2mV	47.47V	0.074uA
43	349.8mV	47.46V	0.078uA	349.5mV	47.33V	0.084uA
44	345.5mV	47.49V	0.105uA	345.3mV	47.76V	0.102uA
45	349.8mV	48.28V	0.077uA	348.5mV	48.05V	0.089uA
46	348.5mV	47.89V	0.106uA	349.4mV	47.86V	0.106uA
47	345.9mV	47.73V	0.114uA	349.1mV	47.02V	0.087uA
48	346.3mV	48.26V	0.107uA	348.6mV	47.74V	0.080uA
49	347.1mV	46.93V	0.110uA	347.4mV	47.66V	0.103uA
50	346.4mV	46.97V	0.112uA	348.8mV	47.75V	0.074uA
51	347.4mV	47.12V	0.112uA	346.7mV	47.97V	0.083uA
52	349.0mV	48.25V	0.109uA	347.6mV	47.53V	0.113uA
53	347.8mV	48.29V	0.088uA	347.8mV	48.22V	0.115uA
54	348.4mV	47.82V	0.108uA	348.4mV	46.94V	0.103uA
55	345.8mV	47.03V	0.091uA	347.0mV	48.40V	0.077uA
56	347.8mV	47.44V	0.104uA	346.4mV	48.04V	0.081uA
57	349.2mV	48.35V	0.079uA	346.3mV	47.41V	0.076uA
58	349.8mV	48.37V	0.077uA	346.2mV	48.05V	0.078uA
59	350.4mV	47.61V	0.092uA	349.7mV	47.15V	0.106uA
60	346.8mV	47.81V	0.101uA	347.4mV	47.15V	0.079uA

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.05.11 ~ 2014.06.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	349.0mV	47.46V	0.077uA	348.9mV	47.52V	0.085uA
62	347.4mV	47.07V	0.073uA	350.2mV	47.25V	0.109uA
63	348.2mV	47.83V	0.095uA	346.0mV	47.34V	0.097uA
64	347.1mV	48.29V	0.105uA	345.5mV	47.49V	0.110uA
65	349.7mV	47.48V	0.109uA	345.8mV	48.20V	0.093uA
66	345.9mV	47.36V	0.106uA	346.2mV	48.51V	0.089uA
67	349.9mV	47.45V	0.100uA	345.7mV	47.94V	0.084uA
68	345.4mV	48.21V	0.080uA	345.9mV	47.49V	0.095uA
69	346.5mV	47.83V	0.074uA	347.0mV	48.13V	0.103uA
70	345.8mV	48.19V	0.088uA	349.7mV	47.06V	0.109uA
71	349.2mV	47.57V	0.108uA	347.5mV	48.08V	0.103uA
72	346.6mV	47.63V	0.091uA	347.6mV	46.94V	0.112uA
73	349.6mV	47.63V	0.109uA	346.8mV	47.21V	0.108uA
74	347.4mV	48.28V	0.088uA	348.0mV	48.31V	0.103uA
75	348.7mV	47.21V	0.089uA	348.7mV	47.73V	0.107uA
76	347.5mV	48.16V	0.107uA	345.5mV	47.06V	0.075uA
77	348.3mV	47.37V	0.106uA	350.1mV	47.80V	0.086uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T140630-034
Part No : SCS520G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<450mV@IF=1A, VB>30V@I=1mA, IR<0.5uA@VR=10V
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2014.06.28 ~ 2014.06.28
Test Standard : JESD22 STANDER Method-B102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	345.9mV	47.85V	0.093uA	345.5mV	47.53V	0.094uA
2	349.6mV	47.39V	0.075uA	345.9mV	48.21V	0.110uA
3	349.5mV	46.91V	0.076uA	349.8mV	48.41V	0.092uA
4	348.0mV	48.18V	0.105uA	347.6mV	47.54V	0.092uA
5	345.6mV	47.41V	0.095uA	349.8mV	47.68V	0.078uA
6	347.1mV	48.24V	0.088uA	345.3mV	47.62V	0.089uA
7	348.6mV	47.01V	0.085uA	348.9mV	46.96V	0.110uA
8	347.1mV	48.02V	0.105uA	349.8mV	48.42V	0.114uA
9	348.2mV	47.83V	0.104uA	345.9mV	47.53V	0.084uA
10	346.3mV	47.88V	0.084uA	346.6mV	48.41V	0.087uA

Made By: Leo Hsia

Approval: Peter Yang